

Notice of References Cited	Application/Control No. 10/804,411	Applicant(s)/Patent Under Reexamination GARRETT, DAVID	
	Examiner Jason M. Perilla	Art Unit 2611	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lei et al, "Reduced Complexity Maximum Likelihood Detection for V-Blast Systems"; IEEE Military Communications Conference, 2003 MILCOM, Vol. 2, pgs. 1386-1391, Oct. 2003.
	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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